

09954809_CLS

Most Frequently Occurring Classifications of Patents Returned
From A Search of 09954809 on September 30, 2003

Original Classifications

7 324/765
5 324/601
3 327/108
3 365/230.05
3 714/736
2 702/85
2 714/726
2 714/727
2 714/740

Cross-Reference Classifications

4 324/638
3 324/158.1
3 324/601
3 324/763
3 714/724
2 324/637
2 326/30
2 326/90
2 327/563
2 327/68
2 356/364
2 365/200
2 365/201
2 365/230.05
2 713/500
2 714/727

PLW's
Report

Combined Classifications

8 324/601
7 324/765
5 324/638
5 365/230.05
4 324/158.1
4 714/724
4 714/727
4 714/736
3 324/637
3 324/763
3 327/108
3 365/201
3 702/85
2 324/627

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2 326/30
2 326/90
2 327/563
2 327/68
2 356/364
2 356/73.1
2 365/189.04
2 365/200
2 702/76
2 713/500
2 714/726
2 714/740

09954809_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09954809 on September 30, 2003

8	324/601	(5 OR, 3 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/600	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
		REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
		RELATIONSHIPS
	324/601	.Calibration
7	324/765	(7 OR, 0 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
		ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
	324/765	..Test of semiconductor device
5	324/638	(1 OR, 4 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/600	IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
		REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
		RELATIONSHIPS
	324/629	.Distributive type parameters
	324/637	..Using transmitted or reflected microwaves
	324/638	...Scattering type parameters (e.g., complex reflection coefficient)
5	365/230.05	(3 OR, 2 XR)
	Class 365 :	STATIC INFORMATION STORAGE AND RETRIEVAL
	365/230.01	ADDRESSING
	365/230.05	.Multiple port access
4	324/158.1	(1 OR, 3 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/158.1	MISCELLANEOUS
4	714/724	(1 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
4	714/727	(2 OR, 2 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

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DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
714/727 ...Boundary scan

4 714/736 (3 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/736 ..Device response compared to expected
fault-free response

3 324/637 (1 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/629 .Distributive type parameters
324/637 ..Using transmitted or reflected microwaves

3 324/763 (0 OR, 3 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/763 ..DUT including test circuit

3 327/108 (3 OR, 0 XR)
Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
327/108 .Current driver

3 365/201 (1 OR, 2 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing

3 702/85 (2 OR, 1 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/85 CALIBRATION OR CORRECTION SYSTEM

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2 324/627 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RES
 PONSE
 RELATIONSHIPS
 324/612 .Parameter related to the reproduction or
 fidelity of a signal affected by a circuit
 under test
 324/627 ..Shielding effectiveness (SE)

2 326/30 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/21 SIGNAL SENSITIVITY OR TRANSMISSION INTEGRITY
 326/30 .Bus or line termination (e.g., clamping,
 impedance matching, etc.)

2 326/90 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/62 INTERFACE (E.G., CURRENT DRIVE, LEVEL SHIFT,
 ETC.)
 326/82 .Current driving (e.g., fan in/out, off chip
 driving, etc.)
 326/89 ..Bipolar transistor
 326/90 ...Bus driving

2 327/563 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
 DEVICES, CIRCUITS, AND SYSTEMS
 327/524 SPECIFIC IDENTIFIABLE DEVICE, CIRCUIT, OR
 SYSTEM
 327/560 .Nonlinear amplifying circuit
 327/563 ..With differential amplifier

2 327/68 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
 DEVICES, CIRCUITS, AND SYSTEMS
 327/1 SPECIFIC SIGNAL DISCRIMINATING (E.G.,
 COMPARING, SELECTING, ETC.) WITHOUT SUBS
 EQUENT CONTROL
 327/50 .By amplitude
 327/63 ..Comparison between plural varying inputs
 327/68 ...Input provides varying reference signal

2 356/364 (0 OR, 2 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/364 BY POLARIZED LIGHT EXAMINATION

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- 2 356/73.1 (1 OR, 1 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/73.1 FOR OPTICAL FIBER OR WAVEGUIDE INSPECTION
- 2 365/189.04 (1 OR, 1 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.01 READ/WRITE CIRCUIT
 365/189.04 .Simultaneous operations (e.g., read/write)
- 2 365/200 (0 OR, 2 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.01 READ/WRITE CIRCUIT
 365/200 .Bad bit
- 2 702/76 (1 OR, 1 XR)
 Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
 TESTING
 702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
 702/57 .Electrical signal parameter measurement syste
 702/66 ..Waveform analysis
 702/75 ...Frequency
 702/76Frequency spectrum
- 2 713/500 (0 OR, 2 XR)
 Class 713 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
 SYSTEMS: SUPPORT
 713/500 CLOCK, PULSE, OR TIMING SIGNAL GENERATION OR
 ANALYSIS
- 2 714/726 (2 OR, 0 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive sca
 design (LSSD))
- 2 714/740 (2 OR, 0 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/738 ..Including test pattern generator
 714/740 ...Having analog signal

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6614237 90
6407542 85
6177804 76
4775977 73
6087843 69
5307284 67
6060888 67
6396285 67
6417674 67
6571187 67
5793213 66
5260947 63
5996102 62
5999008 61
6194911 61
5942922 59
6057716 59
5930735 59
6016566 59
6028438 59
6356096 59
6163223 59
5668819 59
5831440 59
6256760 59
6260166 59
6397354 59
6446230 59
6449033 59
6529844 59
6606158 59
5734613 57
5742557 57
5896330 57
6232815 57
5982827 56
5673275 56
5233564 55
4808913 54
5430400 54
6166569 54
6188227 54
6281699 54
6329833 54
6380533 54
6414496 54
6421624 54
6052810 54

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5818243 54
5561638 53